Implementation strategies for digital design

Chip complexity grows faster than design productivity

From 1980: Design gap

Compound complexity growth rate

(#transistors/chip):

58%/Year

Compound productivity growth rate

(Transistor/Person-month):

21%/Year

→ Team size increases (now 1000)

Productivity leaps are due to the introduction of new design technologies

Time: 70s

Programmable Logic Arrays

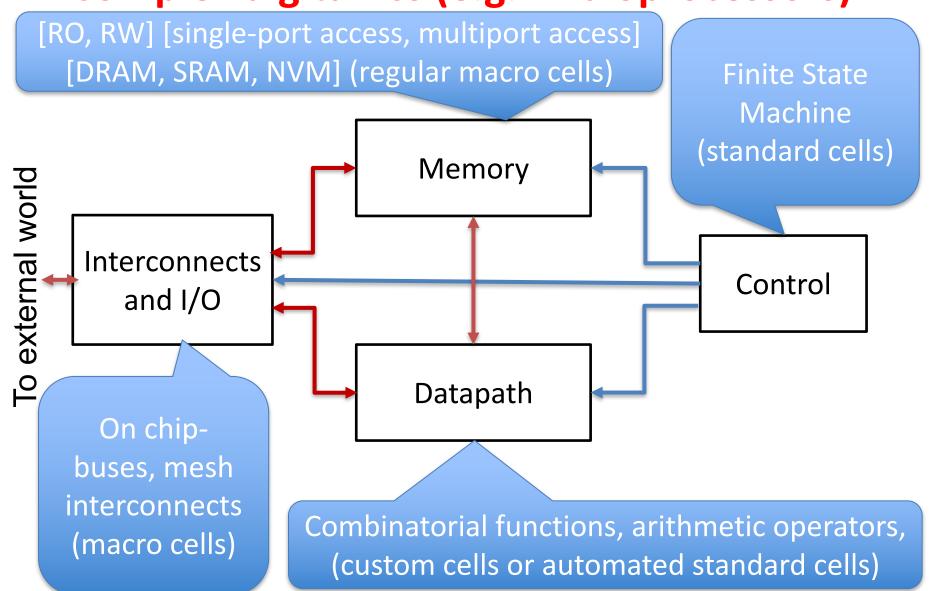
Standard cells

Macro cells, module compilers

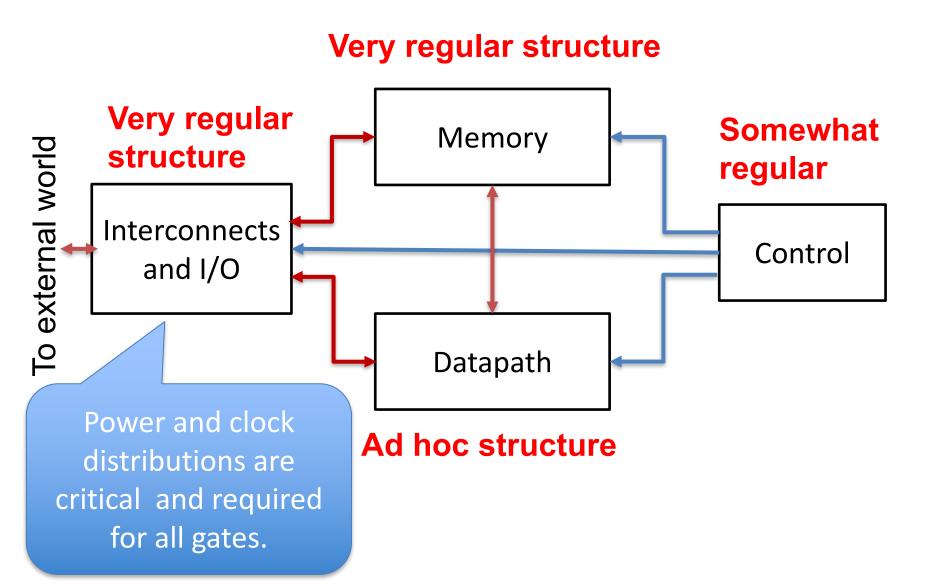
Gate arrays

Reconfigurable hardware

Complex digital ICs (e.g. Microprocessors)



Semiautomatic placement and routing



Intel 4004 – custom design

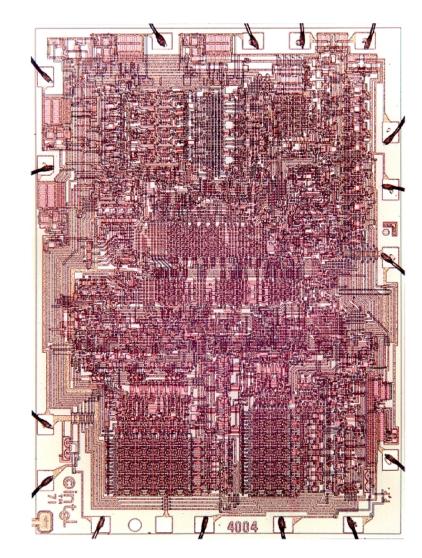
2300 PMOS

10 μ m process

Clock: 108 KHz

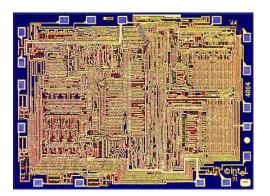
Area:

3 mm x 4 mm

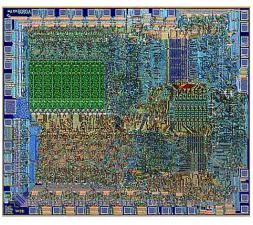


Courtesy Intel

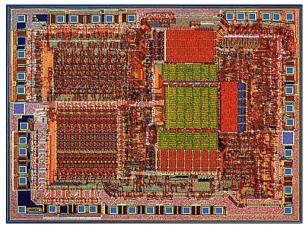
Transition to Automation and Regular Structures



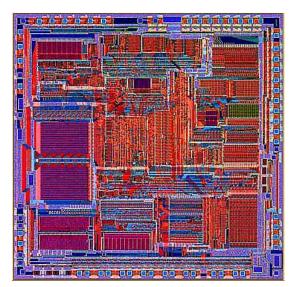
Intel 4004 ('71)



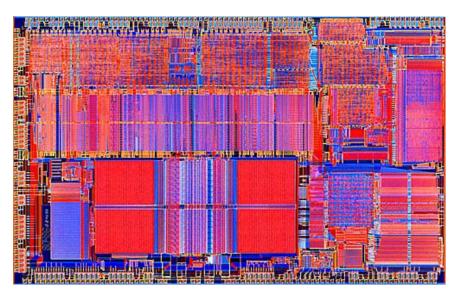
Intel 8080



Intel 8085



Intel 8286



Intel 8486

Courtesy Intel

Tradeoff between flexibility and efficiency

efficiency

Energy

ADVANTAGES of Flexibility (Programmability):

- Reusable design of multiple applications
- Generic hardware with upgradable software

DISADVANTAGES:

- Loss in performance: large overhead and slower operation (instruction decoding)
- Increase in energy consumption: same reason.

Custom Hardwired (fixed at manufacturing)

Configurable HW (parameters)

Application specific processor (DSP, GPU)

Embedded microprocessor

Flexibility

Cost of an integrated circuit

Recurring Expenses (Variable costs)



Proportional to the Sales volume

+ Non Recurring Expenses (Fixed costs)



Independent of the Sales volume

Total cost of 1 chip =

Variable cost of 1 chip +
$$\frac{\text{fixed costs}}{\text{# of chips}}$$

NRE (Fixed Costs) and RE (Variable Costs)

NRE = Time & Person Months required for the design+ production equipment related to the specific chip

RE =
$$\frac{\text{cost of die} + \text{cost of die test} + \text{cost of packaging}}{\text{final test yield}}$$
 % of good chips
$$\frac{\text{cost of die}}{\text{cost of die}} = \frac{\text{cost of wafer}}{\text{#dies per wafer} \times \text{die yield}}$$
 % of good dies

Die Yield

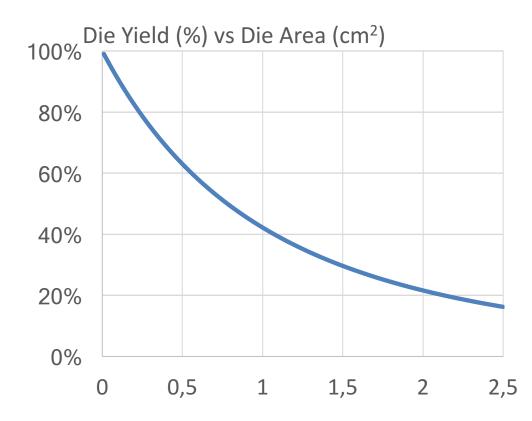
Empirical formula (for a modern CMOS process $\alpha \sim 3$)

Die yield =
$$\left[1 + \frac{\text{\# defects per unit area} \times \text{die area}}{\alpha} \right]^{-\alpha}$$

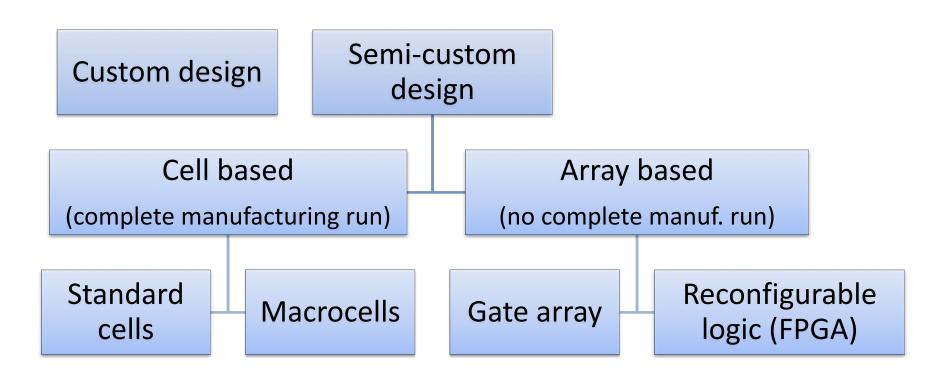
For example:

1 defect/cm²

Die area	Yield		
0.025 cm^2	99%		
0.25 cm^2	78%		
2.5 cm ²	16.2%		



Implementation approaches to digital design



Higher Performance Higher NREs

Higher Flexibility
Higher REs

Custom design

Transistor by transistor design of complete circuit

- [+] High performance
- [-] Time consuming → High cost of design
 - → High time to market

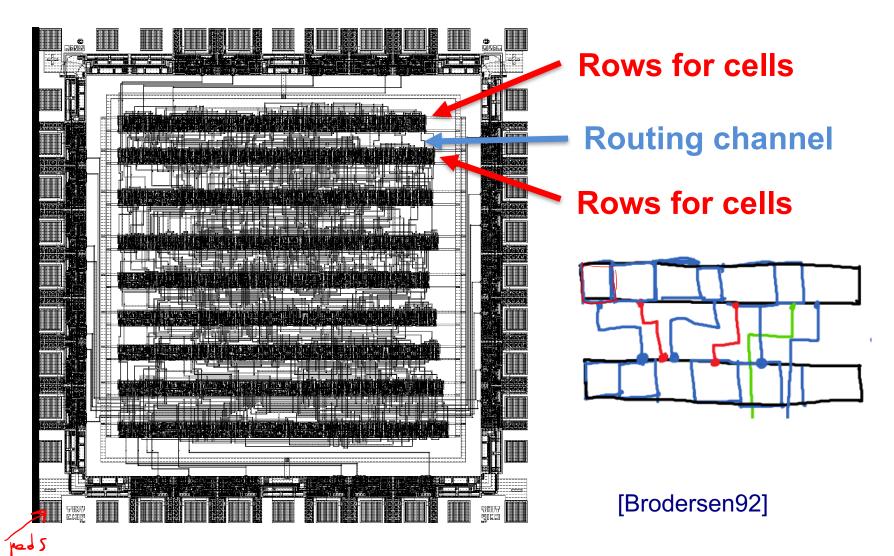
WHEN	Blocks that have to be used many times	e.g. Library Cells	
	Very high volume ICs	e.g. Microprocessors	
	Cost is not an issue	e.g. defense applications e.g. supercomputing applications	

Cell-based semicustom design

We need a library of cells to be used for the design

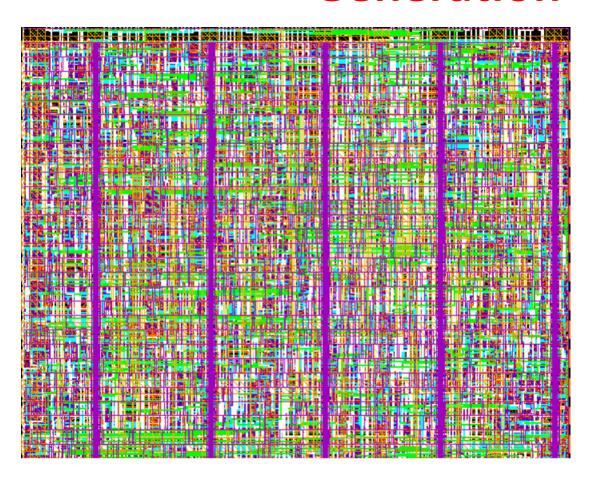
Type of library	
Standard cells	Logic gates, MSI circuits: Decoders, multiplexes, encoders
Macro cells	Memory Bank
Mega cells	Microprocessor, DSP, PCI interface

1st generation Standard Cell — Example

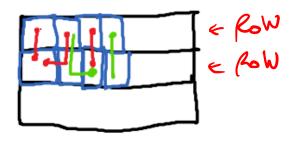


Not very dense – lot of space used by the routing channels

Standard Cell – The New Generation

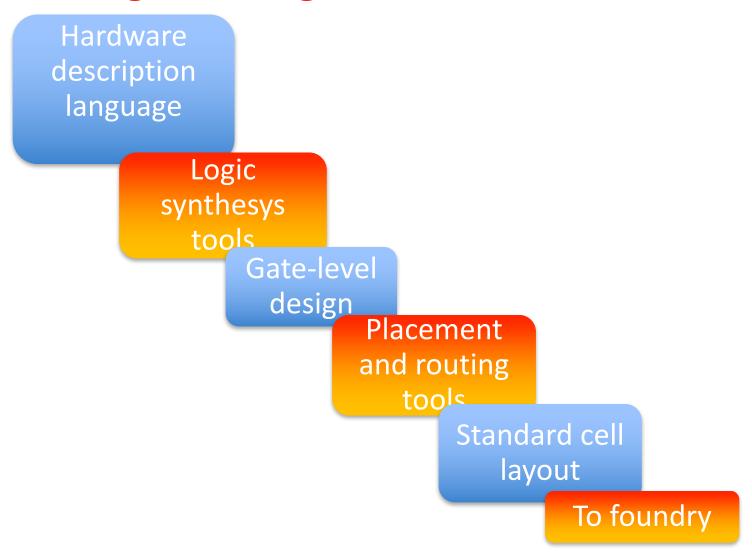


Cell-structure
hidden under
interconnect layers



Much denser structure: no space occupied by routing channels Routing occurs through higher interconnect layers

Design at a high level of abstraction



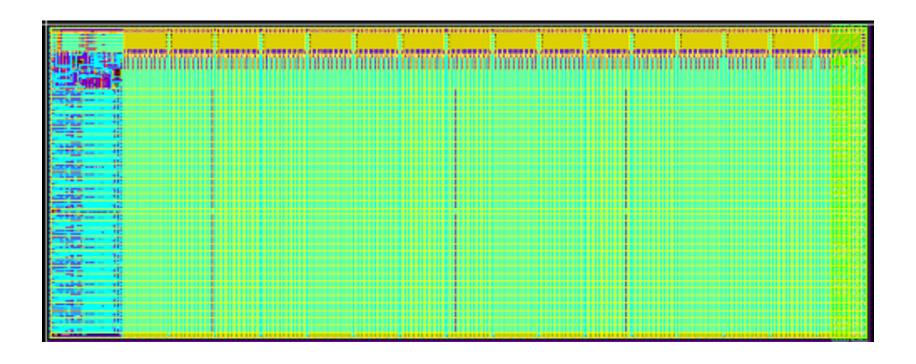
Suitable to Fabless industry model

Fabless company	Design + Testing + Sale	e.g. Marvell, Qualcomm Dialog Semiconductor, Altera, Xilinx		
Foundry	Fabrication + Standard cells for Fabless	e.g. TSMC, UMC, SMIC		
IDM (Integrated Device Manufacturer)	Design + Fabrication + Testing + Sale	e.g. INTEL, Samsung STM		
IP Vendor	Macro cell library Soft Macromodules IP	e.g. ARM		

Macrocells or Macromodules

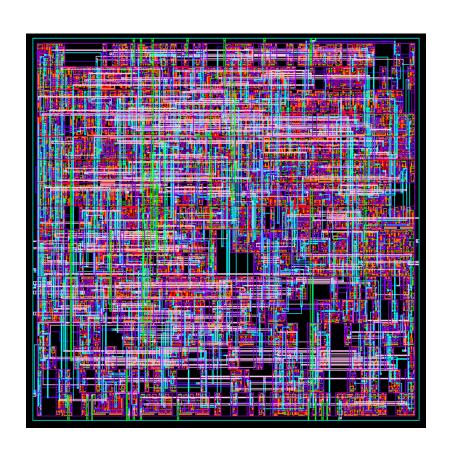
Hard Macrocells	Custom designed for a specific CMOS process	Predetermined functionality AND Predetermined physical implementation
		e.g. embedded microprocessor, embedded memory
Soft Macrocells	Portable to different CMOS Processes (Gate Netlist)	Predetermined functionality but NO physical implementation
		Typically provided by IP vendors [with software tools, testing procedures and tools]

MacroModules

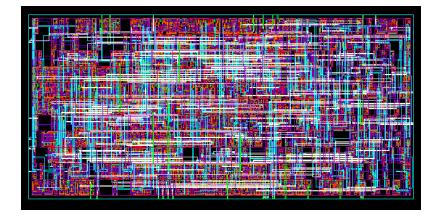


256×32 (or 8192 bit) SRAM Generated by hard-macro module generator

Soft MacroModules and IP



```
string mat = "booth";
directive (multtype = mat);
output signed [16] Z = A * B;
```



Semicustom design flow

FUNCTIONAL IMPLEMENTATION

1.	Design capture	Schematic +VHDL + IP blocks	
2.	Logic Synthesys	Gate netlist + Placement and routing constraints	ر
3.	Pre-layout simulation and verification		
	No	<u>ok</u> Sı	

	PHYSICAL IF	PLEHENTATION
	•	
4.	Floor planning	
5.	Placement and routing	Layout and Masks
6.	Electrical circuit extraction	
7.	Post-layout simulation and verification	
	SEND TO	FOUNDRY

Array-based implementation

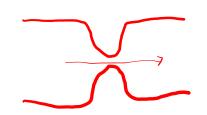
Do not require a complete manufacturing run

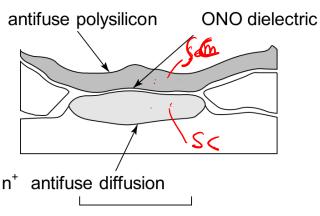
Gate array	Mask Programmable arrays	
(or Sea of gates)	Pre diffused wafers, ONLY Metal layers are missing	
Field Programmable Gate Array (FPGA)	Complete separation between the manufacturing phase and the implementation phase	
	Manufacturing phase has large volumes [+] Short Time-to-market and LOW NRE [-] Performance loss and HIGH RE	

How are cells programmed

Fuse-based FPGA [Write Once]

- Fuse: Normally short circuits (a high current can blow up the fuse)
- Antifuse: Normally OPEN circuit (a high voltage can cause oxide breakdown and short circuit)





Non volatile FPGA

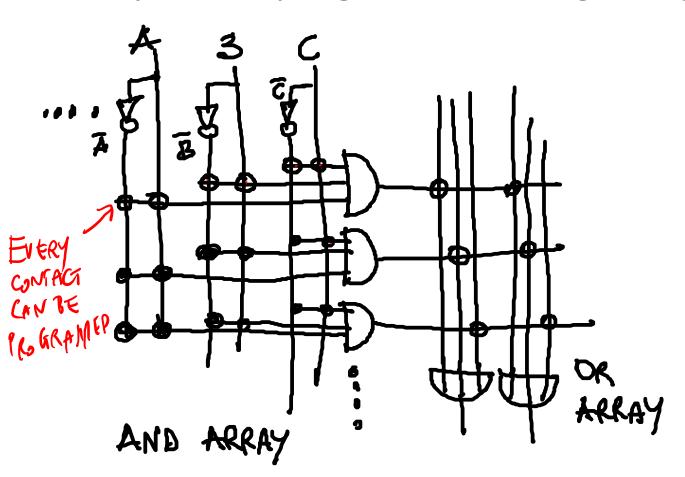
Non Volatile memory that controls on interconnection.

SRAM-based FPGA

(box up table)

What type of logic can be programmed?

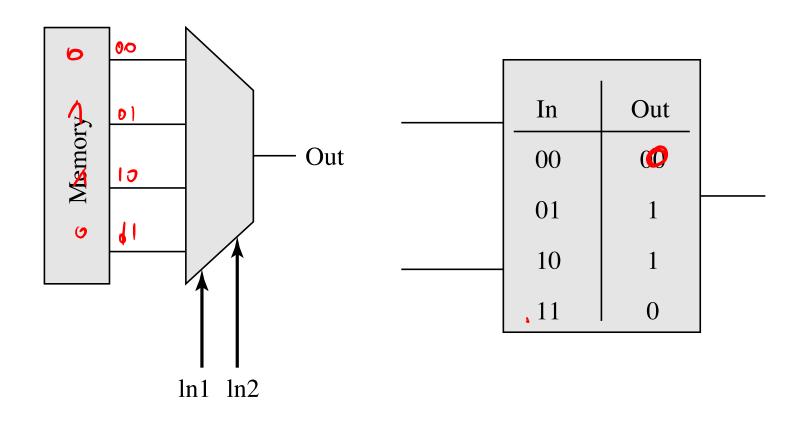
Array-based programmable logic (e.g. PLA, PAL)



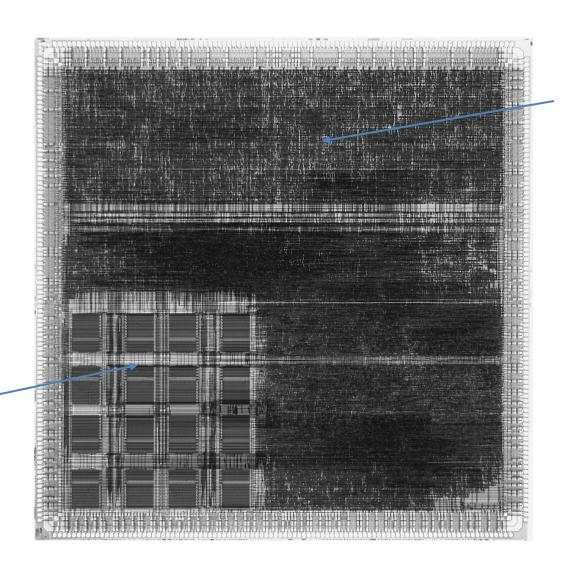
Any combinatorial function [any AND-OR Function]

Cell-based programmable logic

Look Up Table based logic cells: Any combinatorial logic



Sea of gates



Memory

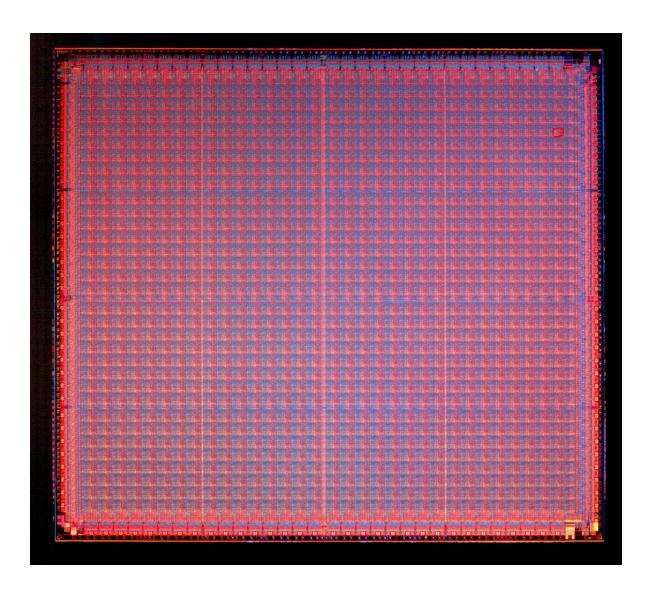
Subsystem

Random Logic

LSI Logic LEA300K (0.6 µm CMOS)

Courtesy LSI Logic

RAM-based FPGA



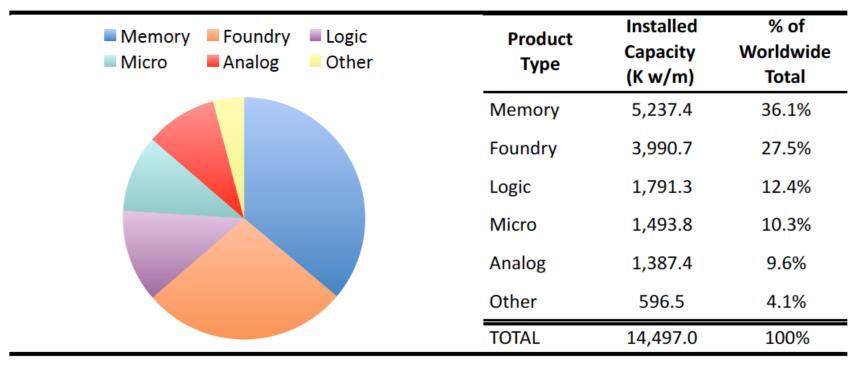
Xilinx XC4000ex

Xilinx Virtex UltraScale

Value	Deliverables
Programmable System Integration	 Up to 5.5M System Logic Cells at 20nm using 2nd generation 3D IC Integrated 100G Ethernet MAC and 150G Interlaken cores
Increased System Performance	 Up to two speed-grade improvement with high utilization 30G transceivers for chip-to-chip, chip-to-optics, 28G backplanes 16G backplane capable transceivers at half the power 2,400 Mb/s DDR4 for robust operation over varying PVT
BOM Cost Reduction	 Up to 50% lower cost – half the cost per port for Nx100G systems VCXO and fractional PLL integration reduces clocking component cost 2,400 Mb/s DDR4 in a mid-speed grade
Total Power Reduction	 Up to 40% lower power vs. previous generation Fine granular clock gating with ASIC-like clocking Enhanced logic cell packing reduces dynamic power
Accelerated Design Productivity	 Footprint compatibility with Kintex UltraScale devices for scalability Seamless footprint migration from 20nm planar to 16nm FinFET Co-optimized with Vivado Design Suite for rapid design closure

IC Production – Installed capacity

Worldwide Capacity by Product Type as of Dec-2012 (Installed Monthly Capacity in 200mm-Equiv. Wafers x1000)



Source: IC Insights

IC Production Breakdown by Region

Regional Capacity by Product Type as of Dec-2012 (Installed Monthly Capacity in 200mm-Equiv. Wafers x1000)

Product	Americas	Europe	Japan	Korea	Taiwan	China	ROW	Total
Analog	323.5	328.3	391.9	31.5	19.2	153.5	139.4	1,387.4
Memory	382.9	29.3	1,109.1	1,821.8	1,194.3	338.3	362.0	5,237.4
Logic	341.1	167.8	704.2	363.1	37.7	70.9	106.5	1,791.3
Micro	727.2	326.4	251.1	26.3	5.1	11.2	146.6	1,493.8
Foundry	296.5	135.5	124.5	254.6	1,899.0	737.3	543.3	3,990.7
Other	50.0	128.5	119.2	67.5	10.1	19.8	201.3	596.5
Total	2,121.3	1,115.7	2,700.1	2,564.7	3,165.4	1,330.8	1,499.0	14,497.0

Source: IC Insights

Korea, Japan ~ 2x Europe Taiwan ~ 3x Europe